

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	3	DOBSON-JOEL-L	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 09:15
S2	4	WANG-EUGENE-Y	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 08:02
S3	17502	(texas adj instrument\$1).asn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 08:02
S4	6	S3 and (equivalen\$5 near2 (index\$3 or indice\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 10:13
S5	417	(equivalen\$5 adj (index\$3 or indice\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 08:04
S6	6	(equivalency adj (index\$3 or indice\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 08:04
S7	396	(equivalen\$2 adj (index\$3 or indice\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 08:04
S8	91	(equivalen\$5 adj (index\$3 or indice\$1)) and ((compare\$2 or comparing or comparison\$1) with (index\$3 or indice\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 08:07
S9	309	(702/81).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 13:11

S10	169	(702/82).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 12:41
S11	352	(702/181).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 08:37
S12	1340	(700/121).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 08:37
S13	222	(700/122).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 08:37
S14	19	(soft adj error\$1 adj test\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 09:15
S15	3	S9 and (equivalen\$5 near2 (index\$3 or indice\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 12:42
S16	1	S10 and (equivalen\$5 near2 (index\$3 or indice\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 10:13
S17	0	S11 and (equivalen\$5 near2 (index\$3 or indice\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 10:13
S18	0	S12 and (equivalen\$5 near2 (index\$3 or indice\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 10:14
S19	0	S13 and (equivalen\$5 near2 (index\$3 or indice\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 10:14

S20	393	(702/84).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 12:41
S21	0	S20 and (equivalen\$5 near2 (index\$3 or indice\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/14 12:42
S22	2	S9 and (equivalen\$5 near2 (index\$3 or indice\$1))	US-PGPUB	OR	OFF	2005/09/14 13:11

10735942_QUAL.txt

6317700 57
6287765 56
5734612 50
6385608 48
6350431 48
5014051 42
4250556 42
6363488 42
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5845315 34
5889593 34
5967986 34

Most Frequently Occurring Classifications of Patents Returned
From A Search of 10735942 on September 14, 2005

Original Classifications

2 324/158.1
2 342/195
2 435/6
2 711/104

Cross-Reference Classifications

3 711/100
2 345/39
2 365/203
2 365/230.06
2 365/230.08
2 430/502
2 536/22.1
2 711/105

Combined Classifications

3 711/100
2 250/208.1
2 324/158.1
2 342/195
2 345/39
2 365/203
2 365/230.06
2 365/230.08
2 430/502
2 430/506
2 430/512
2 435/6
2 536/22.1
2 711/104
2 711/105

Titles of Most Frequently Occurring Classifications of Patents Returned
From A Search of 10735942 on September 14, 2005

3 711/100 (0 OR, 3 XR)
Class 711 : ELECTRICAL COMPUTERS AND DIGITAL PROCESSING
SYSTEMS: MEMORY
711/100 STORAGE ACCESSING AND CONTROL

2 250/208.1 (1 OR, 1 XR)
Class 250 : RADIANT ENERGY
250/200 PHOTOCELLS; CIRCUITS AND APPARATUS
250/206 .Photocell controlled circuit
250/208.1 ..Plural photosensitive image detecting element
arrays

2 324/158.1 (2 OR, 0 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/158.1 MISCELLANEOUS

2 342/195 (2 OR, 0 XR)
Class 342 : COMMUNICATIONS: DIRECTIVE RADIO WAVE SYSTEMS
AND DEVICES
342/175 WITH PARTICULAR CIRCUIT
342/195 .Digital processing

2 345/39 (0 OR, 2 XR)
Class 345 : COMPUTER GRAPHICS PROCESSING, OPERATOR
INTERFACE PROCESSING, AND SELECTIVE VISUAL DISPLAY
SYSTEMS
345/30 PLURAL PHYSICAL DISPLAY ELEMENT CONTROL SYSTEM
(E.G., NON-CRT)
345/33 .segmented display elements
345/35 ..Bar graph
345/39 ...Light-emitting diode segments (LEDs)

2 365/203 (0 OR, 2 XR)
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/189.01 READ/WRITE CIRCUIT
365/203 .Precharge

2 365/230.06 (0 OR, 2 XR)
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/230.01 ADDRESSING
365/230.06 .Particular decoder or driver circuit

2 365/230.08 (0 OR, 2 XR)
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/230.01 ADDRESSING
365/230.08 .Including particular address buffer or latch
circuit arrangement

2 430/502 (0 OR, 2 XR)
Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,
COMPOSITION, OR PRODUCT THEREOF
430/495.1 RADIATION SENSITIVE PRODUCT
430/502 .Two or more radiation-sensitive layers
containing other than that characterized by the
composition
of a single sensitive layer

2 430/506 (1 OR, 1 XR)
Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,

10735942_CLSTITLES.txt

COMPOSITION, OR PRODUCT THEREOF

430/495.1 RADIATION SENSITIVE PRODUCT

430/502 .Two or more radiation-sensitive layers
containing other than that characterized by the
composition of a single sensitive layer

430/503 ...Layers sensitive to different spectral
regions

430/506 ...And containing plural layers sensitive to
the same spectral region

2 430/512 (1 OR, 1 XR)

Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,
COMPOSITION, OR PRODUCT THEREOF

430/495.1 RADIATION SENSITIVE PRODUCT

430/510 .Antihalation or filter layer containing

430/512 ..Filters ultraviolet radiation

2 435/6 (2 OR, 0 XR)

Class 435 : CHEMISTRY: MOLECULAR BIOLOGY AND MICROBIOLOGY

435/4 MEASURING OR TESTING PROCESS INVOLVING ENZYMES
OR MICRO-ORGANISMS; COMPOSITION OR TEST STRIP THEREFORE;

435/6 PROCESSES OF FORMING SUCH COMPOSITION OR TEST STRIP
.Involving nucleic acid

2 536/22.1 (0 OR, 2 XR)

Class 536 : ORGANIC COMPOUNDS -- PART OF THE CLASS
532-570 SERIES

536/1.11 .Carbohydrates or derivatives

536/18.7 ..Nitrogen containing

536/22.1 ...N-glycosides, polymers thereof, metal
derivatives (e.g., nucleic acids, oligonucleotides, etc.)

2 711/104 (2 OR, 0 XR)

Class 711 : ELECTRICAL COMPUTERS AND DIGITAL PROCESSING
SYSTEMS: MEMORY

711/100 STORAGE ACCESSING AND CONTROL

711/101 .Specific memory composition

711/104 ..Solid-state random access memory (RAM)

2 711/105 (0 OR, 2 XR)

Class 711 : ELECTRICAL COMPUTERS AND DIGITAL PROCESSING
SYSTEMS: MEMORY

711/100 STORAGE ACCESSING AND CONTROL

711/101 .Specific memory composition

711/104 ..Solid-state random access memory (RAM)

711/105 ...Dynamic random access memory